

# Octal Buffer/Line Drivers, 3-State

CD74AC/ACT540 - Inverting CD74AC/ACT541 - Non-Inverting

#### **Type Features:**

- Buffered inputs
- Typical propagation delay: 4.5 ns @ V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C, C<sub>L</sub> = 50 pF

The CD54/74AC540, -541, and CD54/74ACT540, -541 octal buffer/line drivers use the RCA ADVANCED CMOS technology. The CD54/74AC/ACT540 are inverting 3-state buffers having two active-LOW output enables. The CD54/74AC/ACT541 are non-inverting 3-state buffers having two active-LOW output enables.

The CD74AC540, -541, and CD74ACT540, -541 are supplied in 20-lead dual-in-line plastic packages (E suffix) and in 20-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Industrial (–40 to +85°C) and Extended Industrial/Military (–55 to +125°C).

The CD54AC540, -541, and CD54ACT540, -541, available in chip form (H suffix), are operable over the -55 to +125°C temperature range.

#### **Family Features:**

- Exceeds 2-kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-resistant CMOS process and circuit design
- Speed of bipolar FAST®/AS/S with significantly reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply.
- ± 24-mA output drive current
  - Fanout to 15 FAST® ICs
  - Drives 50-ohm transmission lines

#### **TRUTH TABLE**

	CD54/74AC	/ACT540
INPUTS		OUTPUTS
ŌE1, ŌE2	Α	Υ
L	L	Н
L	н	L
н	Х	_ Z

#### **TRUTH TABLE**

	CD54/74AC	/ACT541	
INPUTS		OUTPUTS	
OE1, OE2	Α	Υ	
L	L	L	
L	н	Н	
н	X	Z	

H = High Voltage

L = Low Voltage

X = Immaterial

Z = High Impedance

<sup>®</sup>FAST is a Registered Trademark of Fairchild Semiconductor Corp.

MAXIMUM RATINGS, Absolute-Maximum Values:	
DC SUPPLY-VOLTAGE (V <sub>CC</sub> )	–0.5 to 6 V
DC INPUT DIODE CURRENT, $I_{ K }$ (for $V_{ } < -0.5$ or $V_{ } > V_{CC} + 0.5$ V)	±20 mA
DC OUTPUT DIODE CURRENT, $I_{OK}$ (for $V_O < -0.5$ or $V_O > V_{CC} + 0.5$ V)	±50 mA
DC OUTPUT SOURCE OR SINK CURRENT per Output Pin, IO (for VO > -0.5 or VO < VCC + 0.5 V)	±50 mA
DC V <sub>CC</sub> OR GROUND CURRENT (I <sub>CC</sub> or I <sub>GND</sub> )	±100 mA*
PACKAGE THERMAL IMPEDANCE, θJA (see Note 1): E package	69°C/W
M package	58°C/W
STORAGE TEMPERATURE (T <sub>stq</sub> )	–65 to +150°C
LEAD TEMPERATURE (DURINĞ SOLDERING):	
At distance 1/16 $\pm$ 1/32 in. (1.59 $\pm$ 0.79 mm) from case for 10 s maximum	+265°C
Unit inserted into PC board min. thickness 1/16 in. (1.59 mm) with solder contacting lead tips only	+300°C
* For up to 4 outputs per device; add +25 mA for each additional output	

#### **RECOMMENDED OPERATING CONDITIONS:**

For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERICTIC	LIM	LIMITS			
CHARACTERISTIC	MIN.	MAX.	UNITS		
Supply-Voltage Range, V <sub>cc</sub> *: (For T <sub>A</sub> = Full Package-Temperature Range) AC Types ACT Types	1.5 4.5	5.5 5.5	V		
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub>	0	Vcc	V		
Operating Temperature, T <sub>A</sub> :	-55	+125	°C		
Input Rise and Fall Slew Rate, dt/dv at 1.5 V to 3 V (AC Types) at 3.6 V to 5.5 V (AC Types) at 4.5 V to 5.5 V (ACT Types)	0 0 0	50 20 10	ns/V ns/V ns/V		

<sup>\*</sup>Unless otherwise specified, all voltages are referenced to ground.

#### **TERMINAL ASSIGNMENT DIAGRAMS**



NOTE 1: The package thermal impedance is calculated in accordance with JESD 51.

Technical Data _	
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STATIC ELECTRICAL CHARACTERISTICS: AC Series

						AMBIENT	TEMPE	RATURE	(T <sub>A</sub> ) - °(			
CHARACTERISTIC	cs	TEST CO	NDITIONS	V <sub>cc</sub>	+:	25	-40 to	o +85	-55 to	+125	UNITS	
		V, (V)	l <sub>o</sub> (mA)	(v)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
High-Level Input			,	1.5	1.2	_	1.2		1.2			
Voltage	V <sub>iH</sub>			3	2.1	_	2.1	_	2.1		V	
				5.5	3.85	_	3.85	l –	3.85		l	
Low-Level Input				1.5		0.3	_	0.3	-	0.3		
Voltage	VIL	:		3		0.9	_	0.9	<del>-</del>	0.9	V	
				5.5	-	1.65	_	1.65		1.65	]	
High-Level Output			-0.05	1.5	1.4	_	1.4		1.4	_		
Voltage	V <sub>OH</sub>	V <sub>IH</sub>	-0.05	- 3	2.9	_	2.9		2.9			
		or	-0.05	4.5	4.4	_	. 4.4	_	4.4	_	1	
		VIL	-4	3	2.58	_	2.48		2.4	_	] v	
			-24	4.5	3.94	_	3.8	_	3.7		]	
		" " 1	-75	5.5			3.85		_		]	
		#, * }	-50	5.5	_		_		3.85		1	
Low-Level Output		,	0.05	1.5		0.1		0.1	_	0.1		
Voltage	$V_{\text{OL}}$	$V_{OL}$	VIII	0.05	3	_	0.1	_	0.1		0.1	1
		or	0.05	4.5	_	0.1	_	0.1	_	0.1	1	
		Vil	12	3		0.36	_	0.44	_	0.5	V	
			24	4.5	_	0.36	_	0.44		0.5	1	
		(	75	5.5	_		_	1.65		_	]	
		#. * }	50	5.5	_		_	_		1.65	1	
Input Leakage Current	l <sub>i</sub>	V <sub>cc</sub> or GND		5.5	_	±0.1	_	±1	-	±1	μΑ	
3-State Leakage Current	loz	V <sub>IH</sub>										
		V <sub>IL</sub> V <sub>O</sub> =		5.5	_	±0.5	_	±5	_	±10	μΑ	
		or GND										
Quiescent Supply Current, MSI	Icc	V <sub>∞</sub> or GND	0	5.5	_	8	_	80	_	160	μΑ	

<sup>#</sup>Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize

power dissipation.

\* Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

#### STATIC ELECTRICAL CHARACTERISTICS: ACT Series

					AMBIEN	TEMPE	RATURE	(T <sub>A</sub> ) - °(	С	]	
CHARACTERIST	ICS	TEST CONDITIONS		V <sub>cc</sub>	+	25	-40 t	o +85	-55 to	+125	UNITS
			I <sub>o</sub> (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
High-Level Input Voltage	ViH			4.5 to 5.5	2	_	2	_	2	_	v
Low-Level Input Voltage	VIL			4.5 to 5.5		0.8		0.8	_	0.8	v
High-Level Output		ViH	-0.05	4.5	4.4	_	4.4		4.4		
Voltage	V <sub>OH</sub>	or V <sub>IL</sub>	-24	4.5	3.94		3.8		3.7		v
		#, * {	-75	5.5	_		3.85		_		] .
		" )	-50	5.5		_	_		3.85	_	
Low-Level Output Voltage Vol		ViH	0.05	4.5	_	0.1		0.1		0.1	
	Vol	or V <sub>IL</sub>	24	4.5		0.36		0.44	_	0.5	v
		#. * }	75	5.5			_	1.65			] `
		··· \	50	5.5						1.65	
Input Leakage Current	l,	V <sub>CC</sub> or GND		5.5	_	±0.1	_	±1		±1	μА
3-State Leakage Current	loz	VIH  or  VIL  Vo =  Vcc  or  GND		5.5	_	±0.5		±5	_	±10	μΑ
Quiescent Supply Current, MSI	lcc	V <sub>cc</sub> or GND	0	5.5	_	8	_	80		160	μΑ
Additional Quiescent Current per Input P TTL Inputs High 1 Unit Load		V <sub>cc</sub> -2.1		4.5 to 5.5		2.4		2.8		3	mA

<sup>#</sup>Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

\* Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

#### **ACT INPUT LOADING TABLE**

INPUT	UNIT	LOAD*
	540	541
DATA	1.42	0.5
OE1, OE2	1.3	1.3

\*Unit load is  $\Delta l_{CC}$  limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25° C.

SWITCHING CHARACTERISTICS: AC Series; t,, t, = 3 ns, C, = 50 pF

			AMBI	ENT TEMPE	RATURE (1	Γ <sub>A</sub> ) - °C	
CHARACTERISTICS	SYMBOL	(vs	-40 1	lo +85	-55 to	o +125	UNITS
	1 1	(*)	MIN.	MAX.	MIN.	MAX.	}
Propagation Delays: Data to Output AC540	tpLH tpHL	1.5 3.3* 5†	2.4 1.8	77 8.6 6.2	2.4 1.7	85 9.5 6.8	ns
AC541	t <sub>PLH</sub> t <sub>PHL</sub>	1.5 3.3 5	 2.8 2.1	89 9.9 7.1	 2.7 2	98 10.9 7.8	ns
Enable, to Output to Output	t <sub>PZL</sub> t <sub>PZH</sub>	1.5 3.3 5	4.6 3.1	136 16.4 10.9	- 4.5 3	150 18 12	ns
Disable to Output to Output	t <sub>PLZ</sub> t <sub>PHZ</sub>	1.5 3.3 5	3.9 3.1	136 13.6 10.9	3.8 3	150 15 12	ns
Power Dissipation Capacitance AC540 AC541	AC540 — 60 Typ.						
Min. (Valley) V <sub>OH</sub> During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>онv</sub> See Fig. 1	5		V			
Max. (Peak) Vol. During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>OLP</sub> See Fig. 1	5	1 Typ. @ 25°C			V	
Input Capacitance	Cı	_	_	10	_	10	pF
3-State Output Capacitance	Co	_	<u> </u>	15		15	pF

#### SWITCHING CHARACTERISTICS: ACT Series; t,, t, = 3 ns, C, = 50 pF

			AMBI	ENT TEMPE	RATURE (1	۲ <u>۸) - °C</u>	T
CHARACTERISTICS	SYMBOL	V <sub>cc</sub>	-40	o +85	-55 to	=125	UNITS
		(V)	MIN.	MAX.	MIN.	MAX.	]
Propagation Delays: Data to Output ACT540	tpLH tpHL	5†	1.9	6.5	1.8	7.2	ns
ACT541	t <sub>PLH</sub> t <sub>PHL</sub>	5†	2.1	7.5	2.1	8.2	ns
Enable to Output	t <sub>PZL</sub> t <sub>PZH</sub>	5	3.5	12.2	3.4	13.4	ns
Disable to Output	t <sub>PLZ</sub> t <sub>PHZ</sub>	5	3.5	12.2	3.4	13.4	ns
Power Dissipation Capacitance ACT540 ACT541	C <sub>PO</sub> §	<del>-</del>		60 Typ. 60 Typ. 60 Typ. 60 Typ.			pF
Min. (Valley) V <sub>OH</sub> During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>онv</sub> See Fig. 1	5		. V			
Max. (Peak) V <sub>OL</sub> During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>OLP</sub> See Fig. 1	5	1 Typ. @ 25°C			v	
Input Capacitance	Cı	_	T -	10	_	10	pF
3-State Output Capacitance	Co	. –	_	15	_	15	pF

\*3.3 V: min. is @ 3.6 V max. is @ 3 V

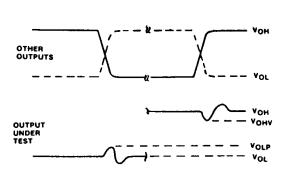
§C<sub>PD</sub> is used to determine the dynamic power consumption, per channel.

For AC series,  $P_D = V_{cc}^2 f_i (C_{PD} + C_L)$ For ACT series,  $P_D = V_{cc}^2 f_i (C_{PD} + C_L) + V_{cc} \Delta I_{cc}$  where

f<sub>i</sub> = input frequency C<sub>L</sub> = output load capacitance

 $V_{CC}$  = supply voltage.

#### PARAMETER MEASUREMENT INFORMATION



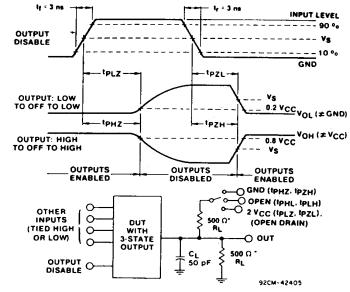
#### NOTES:

- 1. VOHY AND VOLP ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST.

  2. INPUT PULSES HAVE THE FOLLOWING CHARACTERISTICS:
- PRR ≤ 1 MHz, t<sub>7</sub> = 3 ns, t<sub>1</sub> = 3 ns, SKEW 1 ns.

  3. R.F. FIXTURE WITH 700-MHz DESIGN RULES REQUIRED.
  IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED WITH 0.1 pF CAPACITOR. SCOPE AND PROBES REQUIRE 700-MHz BANDWIDTH.

9205-42406



\*FOR AC SERIES ONLY: WHEN  $v_{CC}$  = 1.5 V,  $r_L$  = 1  $k\Omega$ 

Fig. 1 - Simultaneous switching transient waveforms.

Fig. 2 - Three-state propagation delay waveforms and test circuit.

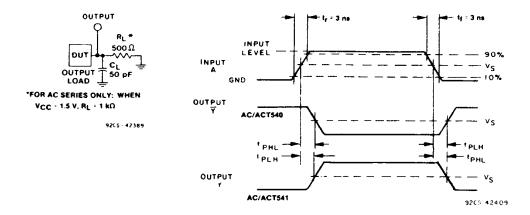


Fig. 3 - Propagation delay times and test circuit.

	CD54/74AC	CD54/74ACT
Input Level	V <sub>cc</sub>	3 V
Input Switching Vottage, Vs	0.5 V <sub>cc</sub>	1.5 V
Output Switching Voltage, V <sub>5</sub>	0.5 V <sub>CC</sub>	0.5 V <sub>cc</sub>

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## **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD54AC541F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54AC541F3A	Samples
CD54ACT540F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54ACT540F3A	Samples
CD54ACT541F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54ACT541F3A	Samples
CD74AC540M	LIFEBUY	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC540M	
CD74AC540M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM		AC540M	Samples
CD74AC541E	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74AC541E	Samples
CD74AC541EE4	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74AC541E	Samples
CD74AC541M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC541M	Samples
CD74AC541M96E4	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC541M	Samples
CD74AC541SM96	ACTIVE	SSOP	DB	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC541SM	Samples
CD74ACT540E	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74ACT540E	Samples
CD74ACT540M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT540M	Samples
CD74ACT541E	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74ACT541E	Samples
CD74ACT541EE4	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74ACT541E	Samples
CD74ACT541M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT541M	Samples
CD74ACT541M96E4	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT541M	Samples
CD74ACT541M96G4	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT541M	Samples
CD74ACT541SM96	ACTIVE	SSOP	DB	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT541SM	Samples

<sup>(1)</sup> The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

## **PACKAGE OPTION ADDENDUM**

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NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF CD54AC541, CD54ACT540, CD54ACT541, CD74AC541, CD74ACT540, CD74ACT541:

Catalog: CD74AC541, CD74ACT540, CD74ACT541

Military: CD54AC541, CD54ACT540, CD54ACT541

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

## **PACKAGE OPTION ADDENDUM**

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• Military - QML certified for Military and Defense Applications



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## TAPE AND REEL INFORMATION





	-
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74AC540M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74AC541M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74AC541SM96	SSOP	DB	20	2000	330.0	16.4	8.2	7.5	2.5	12.0	16.0	Q1
CD74ACT540M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74ACT541M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74ACT541SM96	SSOP	DB	20	2000	330.0	16.4	8.2	7.5	2.5	12.0	16.0	Q1



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## \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74AC540M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74AC541M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74AC541SM96	SSOP	DB	20	2000	356.0	356.0	35.0
CD74ACT540M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74ACT541M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74ACT541SM96	SSOP	DB	20	2000	356.0	356.0	35.0

## **PACKAGE MATERIALS INFORMATION**

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## **TUBE**



\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CD74AC540M	DW	SOIC	20	25	507	12.83	5080	6.6
CD74AC541E	N	PDIP	20	20	506	13.97	11230	4.32
CD74AC541EE4	N	PDIP	20	20	506	13.97	11230	4.32
CD74ACT540E	N	PDIP	20	20	506	13.97	11230	4.32
CD74ACT541E	N	PDIP	20	20	506	13.97	11230	4.32
CD74ACT541EE4	N	PDIP	20	20	506	13.97	11230	4.32

## 14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

## N (R-PDIP-T\*\*)

## PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOIC



- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE PACKAGE



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-150.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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